MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PIFD

MS35N06

Product specification





General Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

General Features

- 60V,35A, RDS(ON)=23mΩ@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Application

- Motor Drive
- Power Tools
- LED Lighting

Reference News

PACKAGE OUTLINE	Pin Configuration	Marking
	G	MSKSEMI 35N06 MS06N
TO-252	s	



Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
lo	Drain Current – Continuous (Tc=25°C)	35	А
lio	Drain Current – Continuous (Tc=100°C)	18	А
Ірм	Drain Current – Pulsed ¹	140	А
Po	Power Dissipation (Tc=25°C)	40	W
PD	Power Dissipation – Derate above 25°C	0.32	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	℃

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		62	°C/W
Reuc	Thermal Resistance Junction to Case		3.1	°C/W

Electrical Characteristics (TJ=25 $^{\circ}$ C , unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60			٧
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient Reference to 25°C , I _D =1mA			0.06		V/°C
lana	Drain Course Leakage Current	V _{DS} =60V , V _{GS} =0V , T _J =25°C			1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =125°C			10	uA
Igss	Gate-Source Leakage Current	V _{GS=} ±20V , V _{DS} =0V			±100	nA



On Characteristics

Rds(on)	Static Drain-Source On-Resistance	V _{GS} =10V , I _D =10A		23	31	mΩ
T (D3(ON)		V _{GS} =4.5V , I _D =5A		30	38	mΩ
VGS(th)	Gate Threshold Voltage	-Vgs=Vps , Ip =250uA	1.0	1.6	2.5	V
△VGS(th)	V _{GS(th)} Temperature Coefficient	VGS-VDS, ID-250UA		-4.6		mV/°C
gfs	Forward Transconductance	VDS=10V , ID=8A		11		S

Dynamic and switching Characteristics

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Qg	Total Gate Charge ^{3, 4}			16.4	
Qgs	Gate-Source Charge ^{3,4}	VDS=30V , VGS=10V , ID=10A		3.1	 nC
\mathbf{Q}_{gd}	Gate-Drain Charge ^{3,4}			3.7	
Td(on)	Turn-On Delay Time ^{3, 4}			4.6	
Tr	Rise Time ^{3,4}	V_{DD} =30V , V_{GS} =10V , R_{G} =6 Ω		14.8	
Td(off)	Turn-Off Delay Time ^{3, 4}	Ip=1A		27.2	 ns
Tf	Fall Time ^{3,4}	ID-TA		7.8	
Ciss	Input Capacitance			1180	
Coss	Output Capacitance	V _{DS} =30V , V _{GS} =0V , F=1MHz		80	 pF
Crss	Reverse Transfer Capacitano	ce		52	
Rg	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz		1.3	 Ω

Drain- Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V , Force Current			35	Α
lsм	Pulsed Source Current	vg-vb-ov , i orce ourrent			70	А
VsD	Diode Forward Voltage	V _G s=0V , I _S =1A , T _J =25°C			1.2	V

Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. V_{DD} =50V, V_{GS} =10V,L=0. 1mH, I_{AS} =23A., R_{G} =25 Ω , Starting T_{J} =25 $^{\circ}$ C
- 3. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 4. Essentially independent of operating temperature.



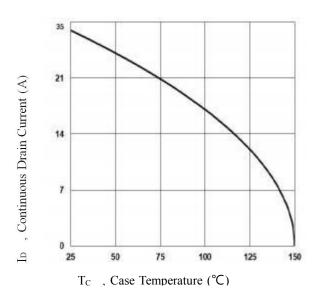
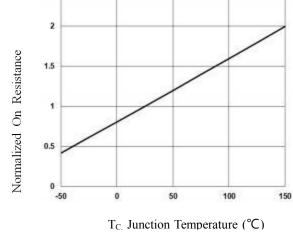
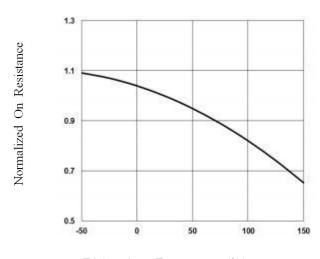


Fig.1 Typical Output Characteristics



2.5

Fig.2 Continuous Drain Current vs. Tc



TJ,Junction Temperature (°ℂ)

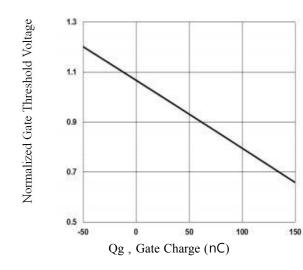


Fig. 4 Gate Charge Waveform



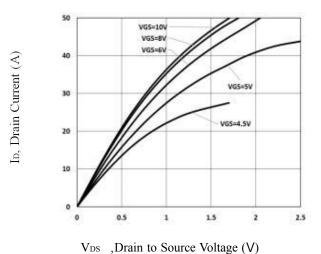


Fig. 5 Typical Output Characteristics

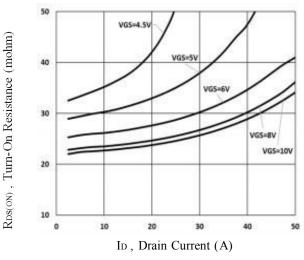
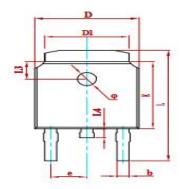


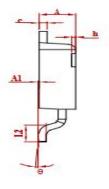
Fig. 6 Turn-On Resistance vs. ID

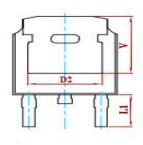




PACKAGE MECHANICAL DATA

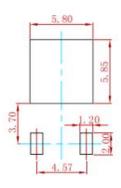






Symbol	Dimensions In Millimeters		Dimensions	In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063	REF.
L4	0.600	1.000	0.024	0.039
Ф	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

Suggested Pad Layout



Note:

- 1 Controlling dimension in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MS35N06	TO-252	2500



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